Issue	Classification

Application/Control No.	Applicant(s)/Patent under Reexamination
09/936,430	AOYAMA ET AL.
Examiner	Art Unit

2634

		IS	SUE CLA	SSIFICAT	ION									
	ORIGINAL		CROSS REFERENCE(S)											
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)											
375	346	375	340											
INTERNA	TIONAL CLASSIFICATION	375	341											
н 0 з	D 1/04	375	200											
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<i></i>	son Joseph 06/07/20		ST	Ly. Chi EPHEN CHIN	Total Claims Allowed: 6									
1.	Alan (S) Instruments Examiner)	114/05		Y PATENT ÉXA O gy center 2 ^{Examiner})	O.G. Print Claim(s)	O.G. Print Fig.								

Jaison Joseph

◯ Claims renumbered in the same order as presented by applicant								☐ CPA			☐ T.D.			☐ R.1.47					
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
	1	1		31			61			91			121			151			181
	2			32]		62			92			122			152			182
	3]		33			63			93_			123			153			183
	4	1		34			64			94			124			154			184
	5]		35			65			95			125			155			185
	6			36			66			96			126			156			186
	7]		37]		67			97			127			157			187
	8			38			68			98			128			158			188
	9]		39			69			99			129			159			189
	10	1		40			70	}		100			130			160			190
	11]		41			71			101			131			161			191
	12]		42			72			102			132			162			192
	13			43			73]		103			133			163			193
	14			44]		74_			104			134			164			194
	15			45			75			105			135			165			195
	16			46]		76			106			136			166			196
	17			47			77			107			137			167			197
	18			48			78			108			138			168			198
	19			49			79			109			139			169			199
	20]		50			80			110			140			170			200
	21			51]		81	}		111			141			171			201
	22			52]		82]		112			142			172			202
	23	}		53]		83			113			143			173			203
	24			54]		84]		114			144			174			204
•	25			55			85]		115			145			175			205
	26			56			86]		116			146			176			206
	27			57			87]		117			147			177			207
	28]		58			88]		118			148			178			208
	29	1		59			89]		119			149			179			209
	30			60			90	<u> </u>		120			150			180			210